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Marker Assisted Gene Pyramiding of Leaf Rust Resistance Genes Lr24 and Lr28 in the Background of Wheat Variety DWR 162 (*Triticum aestivum* L.)

G. Anil Kumar^{1*}, R.R. Hanchinal², Shrinivas Desai¹ and Suma Biradar³

¹Department of Genetics and Plant Breeding, University of Agricultural Sciences, Dharwad – 580005, Karnataka, India

²Chairperson, PPV and FR Authority, Ministry of Agriculture, Government of India, New Delhi, India

³MARS, University of Agricultural Sciences, Dharwad – 580005, Karnataka, India, India



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